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Superhard Mo-AI-N films Composed of Grains with Different Crystallographic Orientations and/or Lattice Structures

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A bstract

This short communication reports on the experiment which demonstrates that superhard nanostructured films with hardness of about 40 GPa and greater can be composed not only of two or more nanocrystalline and/or amorphous phases of different materials, as it is in the case of nanocomposite coatings, but also that can be formed by a mixture of small (<10 nm) nanocrystalline grains of the same material with different crystallographic orientations and/or lattice structures. This finding opens new possibilities to develop advanced nanostructured materials with enhanced physical and functional properties.

Keywords: Mo-Al-N film, Hardness, Structure, Grain size, Mixture of grains

Recently, new superhard two-phase nanocomposite coatings with hardness greater than 40 GPa were successfully prepared using Chemical Vapor Deposition (CVD) and Physical Vapor Deposition (PVD) processes and their combinations¹⁻⁵⁾. First, it was believed that such superhard nanocomposites can be prepared only in the case when both phases of the nanocomposite are hard materials⁶. Very soon it was, however, recognized that this requirement is not necessary condition to produce superhard nanocomposites. A systematic investigation carried out on systems Zr-Cu-N⁷⁾, Zr-Y-N⁸⁾, Cr-Ni-N⁹⁾, Zr-Ni-N¹⁰⁾, Al-Cu-N¹¹⁾ showed that superhard nanocomposites can be formed also in the case when only one phase is hard. This means that there are two groups of the superhard coatings:

- 1) nc-MeN/hard phase (e.g. $a-Si_3N_4$, $a-TiB_2$, etc.)
- 2) nc-MeN/soft phase (e.g. Cu, Y, Ni, Ag, etc.)

here, nc- and a- denote the nanocrystalline and amorphous phase, respectively, and Me=Ti, Zr, W, Cr, Mo, Al, etc., are elements forming hard nitrides.

The main feature of both groups of the superhard coatings is the fact that these two-phase nanocomposite films are composed of two phases of different materials. The hardness H of the films of both groups can be continuously varied from low values of approxi-

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mately 10 GPa to very high values achieving up to 50–70 GPa. These maximum hardnesses are more than twice higher than the hardness of the hardest component of the nanocomposite. This result, which is of great scientific and practical importance, however, opens two fundamental questions: (1) what is the origin of superhardness and (2) if the formation of two nanocrystalline phases of different materials is really only one way how to achieve the superhardness?

This letter is devoted to the second question. It reports on physical and mechanical properties of hard Mo-Al-N films, particularly on the structure-hardness relation in these films. The Mo-Al-N films were sputter deposited using an dc unbalanced magnetron with a composed target, i.e. a round Mo (99.5 % purity) plate of diameter 100 mm with a Al (99.99% purity) fixing ring of internal diameter 80 mm. They were

deposited onto polished and ultrasonically precleaned CSN 15330 steel substrates (a disc 25 mm in diameter and 5-mm thick) under the following conditions: discharge current I_d ranging from 1 to 3 A, substrate bias $u_s = -100$ V, substrate ion current density i_s ranging from 0.6 to 1.2 mA/cm², two values of the substrate temperature $T_s = 300$ and 500 (C, substrate-to-target distance $d_{s-t} = 50$ mm, partial pressure of nitrogen p_{N2} ranging from 0 to 0.5 Pa and total pressure $p_T = p_{Ar} + p_{N2} = 0.5$ Pa. Typical thickness of sputtered films was approximately 4 μ m.

Main results of this experiment follow from the correlation between the hardness and the structure of Mo-Al-N films, see Fig.1. In this figure the XRD patterns from the Mo-Al-N films of different chemical composition and sputtered at different values of p_{N2} and T_s are given, see Table 1. The XRD patterns show that

1) The superhard Mo-Al-N films with ap-

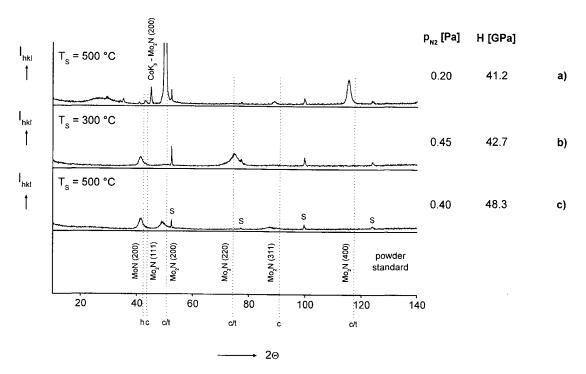


Fig. 1. XRD patterns from superhard Mo-Al-N films sputtered at I_d = 1 A, u_s =-100 V, is=1.2 mA/cm² and a) p_{N2} =0.2 Pa, T_s =500 (C, b) p_{N2} =0.45 Pa, T_s =300 (C and c) p_{N2} =0.4 Pa, T_s =500 (C).

film	р _{N2} [Pa]	T _s	H [GPa]	L _c [mm]	е	Mo [at.%]	Al [at.%]	N [at.%]	N/(Mo + Al)
A	0.20	500	41.2	30.5	0.004	60.1	1.8	37.7	0.61
В	0.45	300	42.7	3	0.026	47	1.9	50.2	1.02
С	0.40	500	48.3	5.4	0.025	49.6	1.8	48.3	0.94

Table 1. Deposition conditions, hardness, structure and chemical composition of three Mo-Al-N films whose XRD patterns are displayed in Fig.1.

proximately the same hardness H exhibit very different structures: 1) a well developed relatively narrow Mo_2N (200) and broad, low-intensity Mo_2N (311) reflections (the film with H = 41.2 GPa, Fig.1a) and (2) (i) broad, low-intensity MoN (200) and Mo_2N (220) reflections (the film with H=42.7 GPa, Fig.1b) and (ii) broad, low-intensity MoN (200), Mo_2N (200) and Mo_2N (311) reflections (the film with H=48.3 GPa, Fig.1c). The same phenomenon was already observed for sputtered superhard Zr-Ni-N¹¹⁾ and Al-Si-Cu-N¹²⁾ films.

2) The superhard Mo-Al-N films with hardness H≥40 GPa are composed of two nc-grains of different lattice structure of the same material: (i) hexagonal MoN (200) and tetragonal and/or cubic Mo₂N (220) grains (Fig.1b) or (ii) hexagonal MoN (200) and tetragonal and/or cubic Mo₂N (200) grains (Fig.1c). Due to overlapping of the tetragonal Mo₂N and cubic (-Mo₂N reflections, it was not possible to determine if the Mo-Al-N film contains only one type of Mo₂N grains, tetragonal or cubic Mo₂N, or a mixture of both types of Mo₂N grains.

3) The orientation of grains in the Mo-Al-N film can also influence its hardness. The Mo-Al-N film composed of MoN (200) and Mo₂N (200) grains are harder than that composed of MoN (200) and Mo₂N (220) grains. At present, however, it i_s not clear what i_s really responsible for higher hardness: the orientation of grains

or the stoichiometry of the film? From Table 1 it i_s seen that the hardest Mo-Al-N film (the film C) is substoichiometric. This fact can also results in a higher hardness of the substoichiometric film compared to that of stoichiometric one.

The main result of this study is a finding that nanostructured materials can be superhard also in the case when they are composed of a mixture of nc-grains of different lattice structure. This means that hard and superhard nanostructured materials can be composed either of grains of different materials or can be formed by a mixture of grains of the same material with different crystallographic orientations and/or different lattice structures. This finding is of fundamental scientific and practical importance. It makes possible to explain the formation of the superhardness in single-phase materials, such as for instance W-Si sputtered films¹³⁾, which cannot be explained by an existence of two phases of different materials as it is in the case of nanocomposite materials.

Very interesting i_s also a correlation between the hardness, grain size and microstrain in Mo-Al-N films, see Fig. 2. Here, the dependences of the microhardness H and microstrain E_g in the film on an average grain size L_c are displayed. The values of E_g and L_c were evaluated from the broadening of the x-ray reflection line with

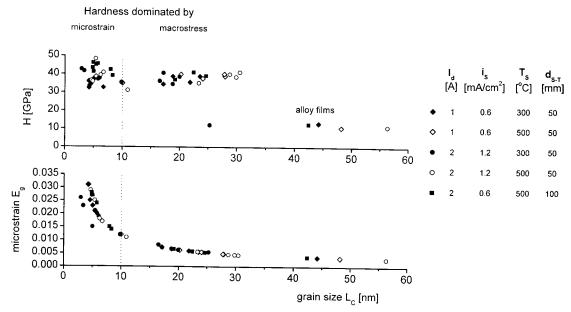


Fig. 2. The microhardness H and the microstrain E_g in sputtered Mo-Al-N films, sputtered at u_s =-100 V, is=0.6 and 1.2 mA/cm², I_d =1 and 2 A, T_s =300 and 500 (C, d_{s-t} =50 and 100 mm and p_{τ} = $p_{\Lambda r}$ + p_{Nz} =0.5 Pa, as a function of the average grain size L_s . The microhardness H was measured using a computer controlled microhardness tester Fisherscope H 100 at a load L=30 mN of the Vicker's diamond indenter.

highest intensity, i.e. from a Full Width at Half Maximum (FWHM), using the Scherrer formula. From Fig. 2 it can be seen that

- a) The hard Mo-Al-N films with the same microhardness H of about 35 GPa can be composed of grains of different size ranging from several nanometers to about 30 nm. The behavior of films with the same H composed of larger (>10 nm) and smaller (\leq 10 nm) grains, however, strongly differs. It is connected with a strong change in (i) the film crystallinity from well developed relatively narrow reflections to broad, low-intensity reflections as shown in Fig. 1 and (ii) the microstrain E_g in the film.
- b) The microstrain E_g increases with decreasing grain size L_c and a dramatic increase in E_g is observed for films composed of grains with $L_c \leq 10$ nm. This strong change in E_g also correlates well with an occurrence of broad, low-intensity reflections in the XRD pattern.

c) Observed experimental data clearly demonstrate that there i_s no simple relation between the film hardness and the average size of grains. For more details, see for instance¹⁴⁾.

Recently, it was shown that a decrease in the grain size L_c below 10 nm results in dramatic changes in magnitude of the macrostress σ generated in the hard film during its growth. The superhard 4 µm thick Al-Cu-N film with hardness of 47 GPa, composed of small (<10 nm) grains, exhibits a low compressive macrostress of about -0.2 GPa. On the contrary, the superhard 4 (m thick Zr-Cu-N film with hardness of 54 GPa, composed of larger (\approx "30 nm) grains, exhibit a high compressive macrostress of about -4 GPa¹⁵⁾. Therefore, the dependence $H=f(L_c \le$ in Fig.2 is divided into two regions where the microhardness is dominated either by the macrostress σ in films composed of grains with L_c (10 nm or by the microstrain E_g in films composed of grains with L_c>10 nm. Thi_s finding i_s also of fundamental importance and opens a new stage in investigation of hard nanostructured coatings. Therefore, a considerable attention i_s now concentrated particularly on (i) the grain size dependent phenomena and their correlations with properties of coatings and (ii) the control of energy delivered to the film during its growth. Also, the macrostress σ , generated in the Mo-Al-N film during its growth, was not so far measured and i_s now under study.

In summary, the investigation of the sputtered Mo-Al-N films showed that nanostructured materials can be superhard in the case when they are composed of a mixture of nc-grains of of the same material with different crystallographic orientations and/or different lattice structures. This finding is of great scientific and technical importance because it (1) widens our knowledge on enhanced properties of nanostructured materials, (2) gives a new insight into the origin of superhardness and (3) makes it possible to explain the superhardness of single-phase materials when the concept of superhardness based on different phases of different materials, valid for nanocomposite films, cannot be used.

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